

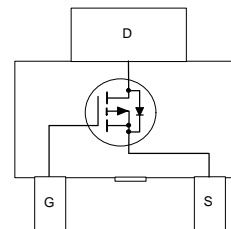
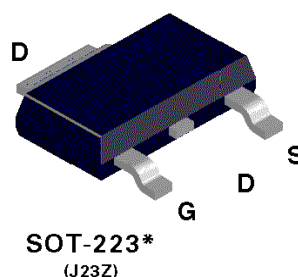
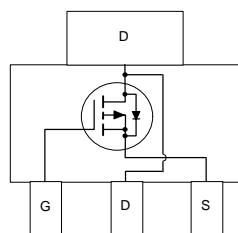
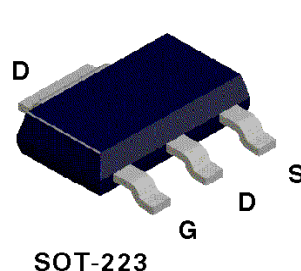
## NDT456P P-Channel Enhancement Mode Field Effect Transistor

### General Description

Power SOT P-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, high cell density, DMOS technology. This very high density process is especially tailored to minimize on-state resistance and provide superior switching performance. These devices are particularly suited for low voltage applications such as notebook computer power management, battery powered circuits, and DC motor control.

### Features

- -7.5 A, -30 V.  $R_{DS(ON)} = 0.030 \Omega$  @  $V_{GS} = -10$  V  
 $R_{DS(ON)} = 0.045 \Omega$  @  $V_{GS} = -4.5$  V.
- High density cell design for extremely low  $R_{DS(ON)}$ .
- High power and current handling capability in a widely used surface mount package.



### Absolute Maximum Ratings $T_A = 25^\circ\text{C}$ unless otherwise noted

Symbol	Parameter	NDT456P	Units
$V_{DS}$	Drain-Source Voltage	-30	V
$V_{GS}$	Gate-Source Voltage	$\pm 20$	V
$I_D$	Drain Current - Continuous (Note 1a)	$\pm 7.5$	A
	- Pulsed	$\pm 20$	
$P_D$	Maximum Power Dissipation (Note 1a)	3	W
	(Note 1b)	1.3	
	(Note 1c)	1.1	
$T_J, T_{STG}$	Operating and Storage Temperature Range	-65 to 150	$^\circ\text{C}$

### THERMAL CHARACTERISTICS

$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient (Note 1a)	42	$^\circ\text{C/W}$
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case (Note 1)	12	$^\circ\text{C/W}$

# Electrical Characteristics (T<sub>A</sub> = 25°C unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
<b>OFF CHARACTERISTICS</b>						
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> = 0 V, I <sub>D</sub> = 250 μA	-30			V
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = -24 V, V <sub>GS</sub> = 0 V			-1	μA
		T <sub>J</sub> = 55°C			-10	μA
I <sub>GSSF</sub>	Gate - Body Leakage, Forward	V <sub>GS</sub> = 20 V, V <sub>DS</sub> = 0 V			100	nA
I <sub>GSSR</sub>	Gate - Body Leakage, Reverse	V <sub>GS</sub> = -20 V, V <sub>DS</sub> = 0 V			-100	nA
<b>ON CHARACTERISTICS</b> (Note 2)						
V <sub>GS(th)</sub>	Gate Threshold Voltage	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = -250 μA	-1	-1.5	-3	V
		T <sub>J</sub> = 125°C	-0.5	-1.1	-2.6	
R <sub>DS(ON)</sub>	Static Drain-Source On-Resistance	V <sub>GS</sub> = -10 V, I <sub>D</sub> = -7.5 A		0.026	0.03	Ω
		T <sub>J</sub> = 125°C		0.035	0.054	
		V <sub>GS</sub> = -4.5 V, I <sub>D</sub> = -6 A		0.041	0.045	
I <sub>D(on)</sub>	On-State Drain Current	V <sub>GS</sub> = -10 V, V <sub>DS</sub> = -5 V	-20			A
		V <sub>GS</sub> = -4.5 V, V <sub>DS</sub> = -5 V	-10			
G <sub>fs</sub>	Forward Transconductance	V <sub>GS</sub> = -10 V, I <sub>D</sub> = -7.5 A		13		S
<b>DYNAMIC CHARACTERISTICS</b>						
C <sub>iss</sub>	Input Capacitance	V <sub>DS</sub> = -15 V, V <sub>GS</sub> = 0 V, f = 1.0 MHz		1440		pF
C <sub>oss</sub>	Output Capacitance			905		pF
C <sub>rss</sub>	Reverse Transfer Capacitance			355		pF
<b>SWITCHING CHARACTERISTICS</b> (Note 2)						
t <sub>D(on)</sub>	Turn - On Delay Time	V <sub>DD</sub> = -15 V, I <sub>D</sub> = -7 A, V <sub>GEN</sub> = -10 V, R <sub>GEN</sub> = 12 Ω		10	20	ns
t <sub>r</sub>	Turn - On Rise Time			65	120	ns
t <sub>D(off)</sub>	Turn - Off Delay Time			70	130	ns
t <sub>f</sub>	Turn - Off Fall Time			70	130	ns
Q <sub>g</sub>	Total Gate Charge	V <sub>DS</sub> = -10 V, I <sub>D</sub> = -7.5 A, V <sub>GS</sub> = -10 V		47	67	nC
Q <sub>gs</sub>	Gate-Source Charge			5		nC
Q <sub>gd</sub>	Gate-Drain Charge			12		nC

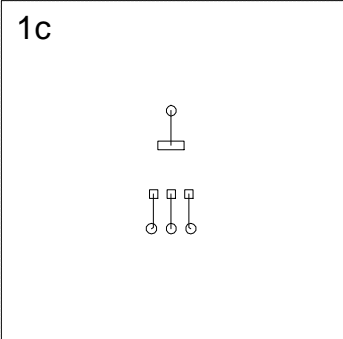
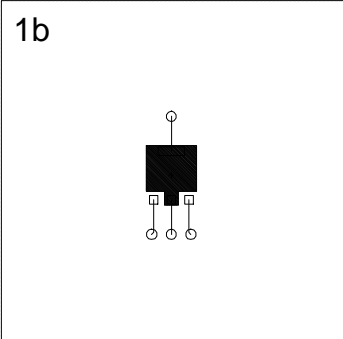
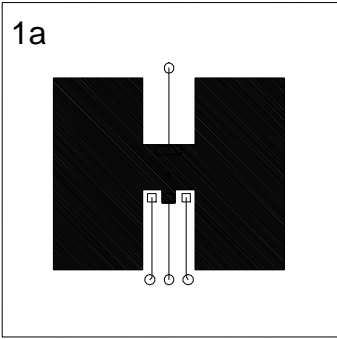
Electrical Characteristics (T<sub>A</sub> = 25°C unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
DRAIN-SOURCE DIODE CHARACTERISTICS AND MAXIMUM RATINGS						
I <sub>S</sub>	Maximum Continuous Drain-Source Diode Forward Current				-2.5	A
V <sub>SD</sub>	Drain-Source Diode Forward Voltage	V <sub>GS</sub> = 0 V, I <sub>S</sub> = - 2.5 A (Note 2)		- 0.85	-1.2	V
t <sub>rr</sub>	Reverse Recovery Time	V <sub>GS</sub> = 0 V, I <sub>F</sub> = - 2.5 A dI <sub>F</sub> /dt = 100 A/μs			140	ns

Notes:

1.  $P_D(t) = \frac{T_J - T_A}{R_{\theta JA}(t)} = \frac{T_J - T_A}{R_{\theta JC} + R_{\theta CA}(t)} = I_D^2(t) \times R_{DS(ON)@T_J}$  R<sub>θJA</sub> is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R<sub>θJC</sub> is guaranteed by design while R<sub>θCA</sub> is defined by users. For general reference: Applications on 4.5"x5" FR-4 PCB under still air environment, typical R<sub>θJA</sub> is found to be:

- a. 42°C when mounted on a 1 in<sup>2</sup> pad of 2oz copper.
- b. 95°C when mounted on a 0.066in<sup>2</sup> pad of 2oz copper.
- c. 110°C/W when mounted on a 0.00123in<sup>2</sup> pad of 2oz copper.



Scale 1 : 1 on letter size paper

2. Pulse Test: Pulse Width ≤ 300μs, Duty Cycle ≤ 2.0%.

## Typical Electrical Characteristics

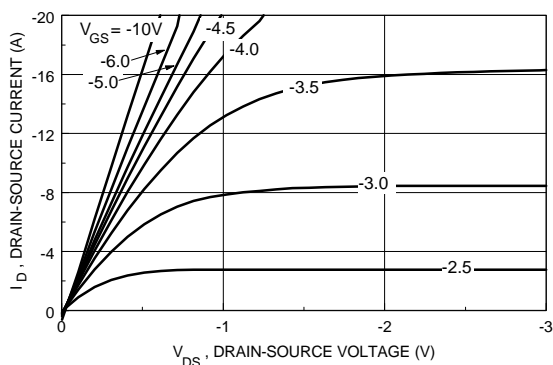


Figure 1. On-Region Characteristics.

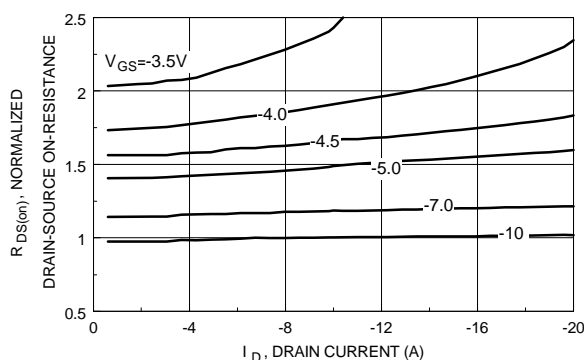


Figure 2. On-Resistance Variation with Gate Voltage and Drain Current.

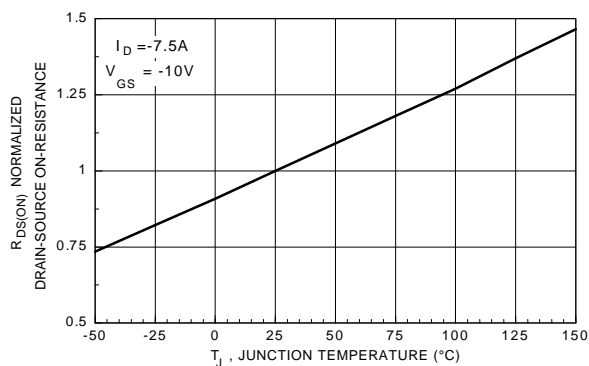


Figure 3. On-Resistance Variation with Temperature.

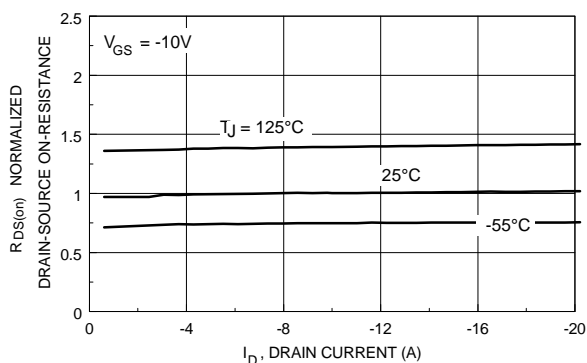


Figure 4. On-Resistance Variation with Drain Current and Temperature.

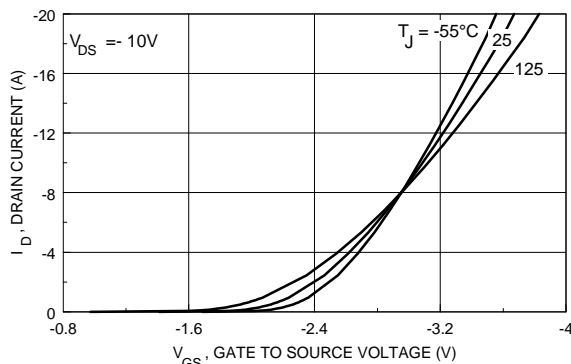


Figure 5. Transfer Characteristics.

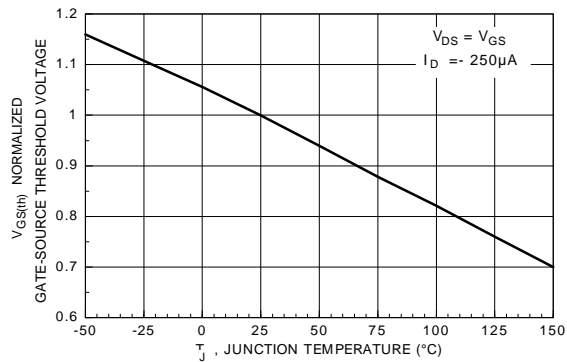
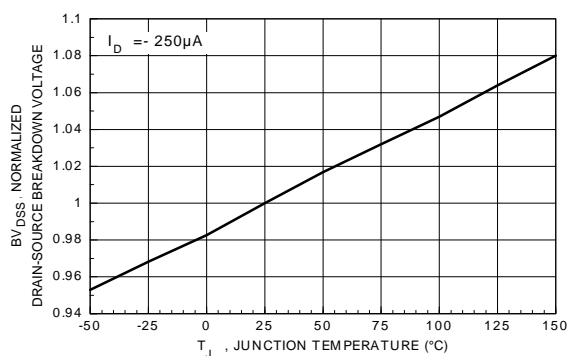
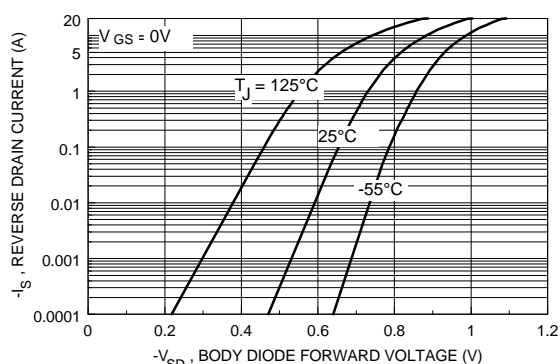


Figure 6. Gate Threshold Variation with Temperature.

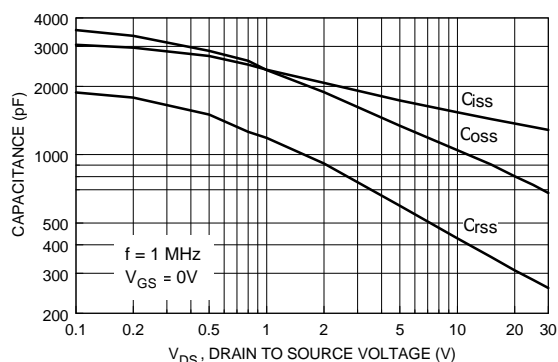
## Typical Electrical Characteristics



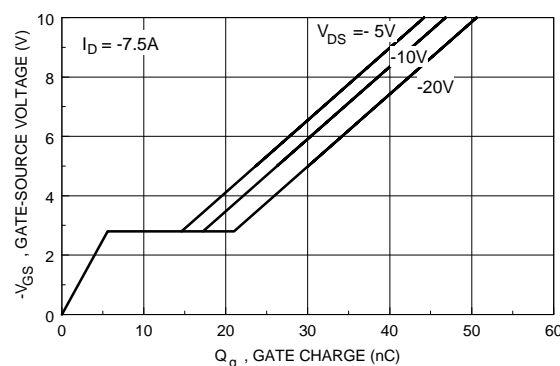
**Figure 7. Breakdown Voltage Variation with Temperature.**



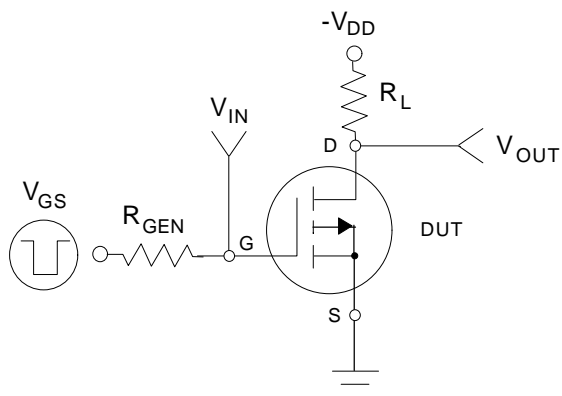
**Figure 8. Body Diode Forward Voltage Variation with Current and Temperature.**



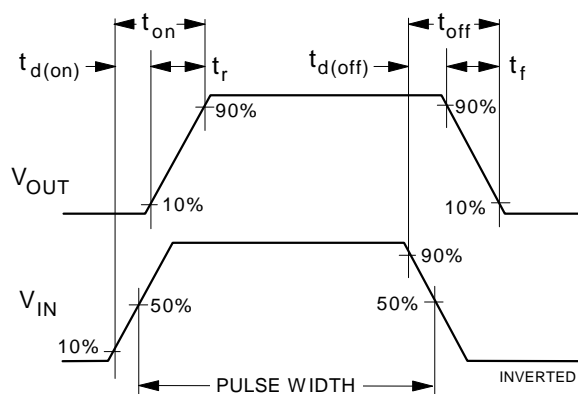
**Figure 9. Capacitance Characteristics.**



**Figure 10. Gate Charge Characteristics.**



**Figure 11. Switching Test Circuit.**



**Figure 12. Switching Waveforms.**

## Typical Thermal Characteristics

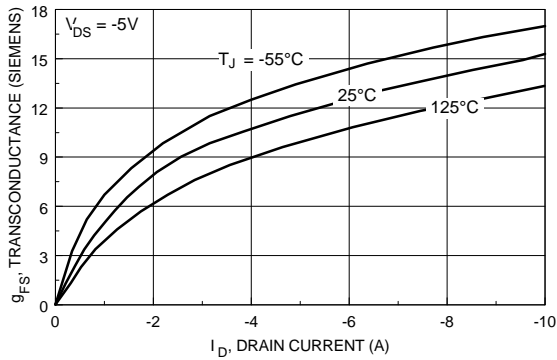


Figure 13. Transconductance Variation with Drain Current and Temperature.

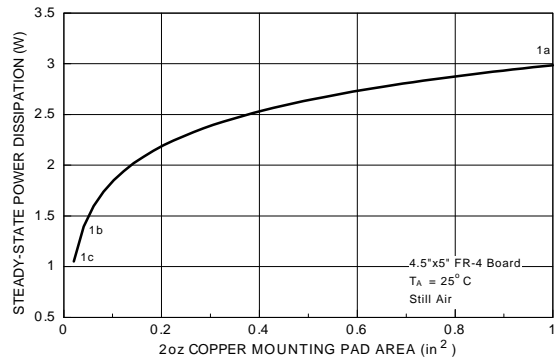


Figure 14. SOT-223 Maximum Steady-State Power Dissipation versus Copper Mounting Pad Area.

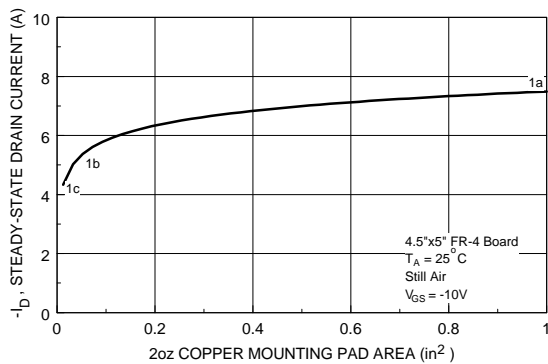


Figure 15. Maximum Steady-State Drain Current versus Copper Mounting Pad Area.

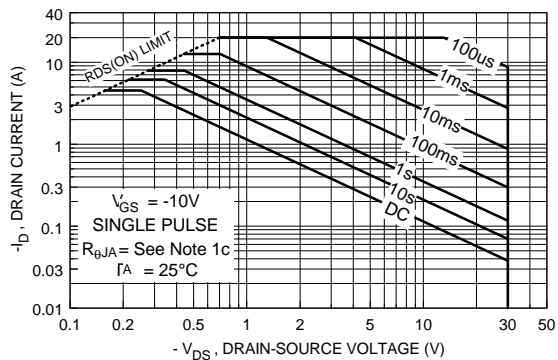


Figure 16. Maximum Safe Operating Area.

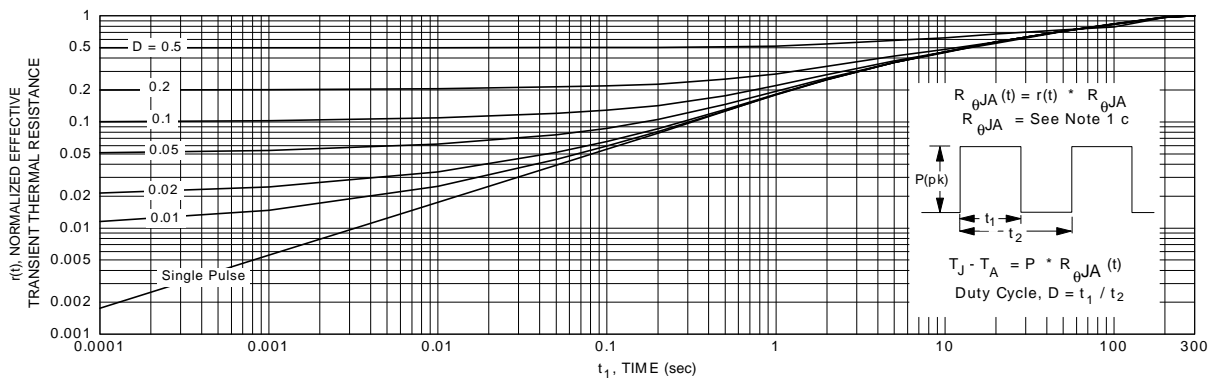


Figure 17. Transient Thermal Response Curve.

Note: Thermal characterization performed using the conditions described in note 1c. Transient thermal response will change depending on the circuit board design.

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